

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE										ATTY. DOCKET NO. ARC9-2000-0066-US2										SERIAL NO. 10/765, Not yet assigned 545									
LIST OF PRIOR ART CITED BY APPLICANT (Use several sheets if necessary)															APPLICANT BAGLIN, John E.E.														
															FILING DATE Filed Herewith										GROUP not yet assigned 2829				
U.S. PATENT DOCUMENTS																													
EXAMINER INITIAL				DOCUMENT NUMBER								DATE		NAME								CLASS		SUBCLASS		FILING DATE IF APPROPRIATE			
LAC		A		5	0	7	9	6	6	2	01/07/92		Kawakami et al.																
↑				5	5	5	0	1	0	1	08/27/96		Nagata e al.																
				6	0	7	7	6	1	8	06/20/00		Sakamina et al.																
LAC				6	3	1	7	3	0	2	11/13/01		Van Kesteren et al.																
FOREIGN PATENT DOCUMENTS																													
				DOCUMENT NUMBER								DATE		COUNTRY								CLASS		SUBCLASS		TRANSLATION			
																										YES NO			
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)																													
		B		Yimin Guo et al. in "Low Fringe-Field and Narrow Track MR Heads", IEEE Transactions on Magnetics, Vol. 33, No. 5, Sept. 1997, pp. 2827-9.																									
		C		G.J. Athas et al. "Focused Ion Beam System for Automated MEMS Prototyping and Processing", Proc. SPIE - Int. Soc. Opt. Eng. (USA), Vol. 3223, 1997, pp. 198-207.																									
		D		Charles Partee et al., "Off-Track Response Versus Shield Width at the ABS for MR Heads", IEEE Transactions on Magnetics (USA), Vol. 33, No. 5, Pt. 1, Sept. 1997, pp. 2887-9.																									
		E		W.M. Kaminsky et al., "Patterning Ferromagnetism in Ni ₈₀ Fe ₂₀ Films via 30 keV Ga ⁺ on Irradiation", Applied Physics Letters, March 30 2000.																									
EXAMINER L. AC															DATE CONSIDERED 7/8/4														
<p>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>																													